

Chapter 6: Basic radiation detectors

Set of 60 slides based on the chapter authored by
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of the IAEA publication (ISBN 978–92–0–143810–2):
Nuclear Medicine Physics:
A Handbook for Teachers and Students

Objective: To familiarize the student with the fundamental concepts
of basic radiation detectors



IAEA
International Atomic Energy Agency

Slide set prepared in 2015
by J. Schwartz (New York,
NY, USA)

- 6.1. Introduction
- 6.2. Gas filled detectors
- 6.3. Semiconductor detectors
- 6.4. Scintillation detectors and storage phosphors

6.1. INTRODUCTION

6.1.1. Radiation detectors — complexity and relevance

- ❑ Radiation detectors are of paramount importance in nuclear medicine

- ❑ The detectors provide a wide range of information including:
 - Radiation dose of a laboratory worker
 - Positron emission tomography (PET) image of a patient

- ❑ Consequently, detectors with strongly differing specifications are used

6.1. INTRODUCTION

6.1.2. Interaction mechanisms, signal formation and detector type

☐ Radiation detectors

- Sensors that produce signals upon interaction with radiation
- Signals can be processed electronically to give requested information

☐ X-rays & γ -rays interaction mechanisms

- Photoelectric effect
- Compton scattering
- Pair production
- Relative importance depends on
 - Radiation energy
 - Interaction medium
- Result in production of energetic electrons
 - These will eventually transfer their energy to interaction medium by ionization and excitation



6.1. INTRODUCTION

6.1.2. Interaction mechanisms, signal formation and detector type

- ❑ Charged particles transfer their energy by ionization & excitation
- ❑ Ionization results in
 - Charge carriers production:
 - ✓ Electrons and ions in a gaseous detection medium
 - ✓ Electrons and holes in a semiconductor material
 - ✓ Light quanta emission in scintillators
- ❑ Radiation detectors
 - Charge or current forms signal
 - Signal created by charge motion in applied electric field
 - ✓ Gas filled detectors
 - ✓ Semiconductor detectors
 - Light emission observed using light sensor that produces charge or current
 - ✓ Scintillation detectors

6.1. INTRODUCTION

6.1.3. Counting, current, integrating mode

- ❑ Radiology / radiotherapy radiation detectors
 - Operated in current mode
 - Intensities too high for individual counting of events
- ❑ Nuclear medicine
 - Primarily use counting mode
 - Energy information
 - Arrival time information
- ❑ Personal dosimeters
 - Detector used in integrating mode
 - Dose is measured monthly
 - Information extracted much later after actual interaction

6.1. INTRODUCTION

6.1.4. Detector requirements

- Radiation detector quality expressed in terms of
 - Sensitivity
 - Energy resolution
 - Time and position resolution
 - Counting rate performance

6.1. INTRODUCTION

6.1.4. Detector requirements

6.1.4.1. Sensitivity

- Sensitivity depends on
 - Subtended solid angle
 - Detector efficiency for radiation interaction
 - Relevant energy range is ~30–511 keV, where it's governed by:
 - Photoelectric effect
 - Attenuation length (cm) $\sim \rho Z_{eff}^{3-4}$
 ρ = density, Z_{eff} = effective atomic number of the compound
 - Compton scattering
 - Almost independent of Z
 - Proportional to ρ
 - ρ of gas-filled detector is 3 orders of magnitude smaller than for solid state detector
 - Need highest possible ρ and Z_{eff} at 511 keV

6.1. INTRODUCTION

6.1.4. Detector requirements

6.1.4.2. Energy, time and position resolution

□ Energy resolution

- Strongly coupled to number of information carriers
- Number of information carriers
 - Given by $N = E/W$
 - E = Radiation energy
 - W = Mean energy needed to produce information carrier
 - Largest number produced in semiconductors
 - Smallest number produced in inorganic scintillators + PMT's

6.1. INTRODUCTION

6.1.4. Detector requirements

6.1.4.2. Energy, time and position resolution

- Mean energies W to produce information carriers

| Detector type | W (eV) |
|--|----------|
| Gas filled (electron–ion) | 30 |
| Semiconductor (electron–hole) | 3 |
| Inorganic scintillator (light quantum) | 25 |
| Inorganic scintillator + PMT (electron) | 100 |
| Inorganic scintillator + Si diode (electron–hole pair) | 35 |

6.1. INTRODUCTION

6.1.4. Detector requirements

6.1.4.2. Energy, time and position resolution

□ Energy resolution definition:

$$\frac{\Delta E}{E} = \frac{\Delta N}{N} = 2.35 \sqrt{\frac{FW}{E}}$$

- $\Delta E = \text{FWHM}$
- $N = E/W$
- $\Delta N = 2.35\sigma$
- $\sigma^2 = FN$
- $F = \text{Fano factor}$
 - Gas-filled detectors $F = 0.05\text{--}0.20$
 - Semiconductors $F \approx 0.12$
 - Scintillator $F = 1$

6.1. INTRODUCTION

6.1.4. Detector requirements

6.1.4.2. Energy, time and position resolution

□ Time resolution

- Mainly important for PET in nuclear medicine
- Time resolution depends on 2 main factors
 - Rise time of the signal pulses
 - Height of the signal pulses
 - Important because there is also noise
 - Easier to determine pulse position when the pulse is higher relative to noise
 - Time jitter due to pulse height (energy) variation is less important
- Inorganic Scintillators detectors preferred because they have
 - Fast response
 - Fast rise time
 - Light sensors' fast response

6.1. INTRODUCTION

6.1.4. Detector requirements

6.1.4.2. Energy, time and position resolution

□ Position resolution

- Most easily obtained by pixelating detector at pitch corresponding to requested resolution
- In nuclear medicine, important in:
 - Gamma camera /SPECT
 - PET detection systems
 - Use of monolithic scintillator blocks recently studied
 - Light detection by pixelated sensors
 - Analogous to gamma camera
 - Broad light distribution measured using pixels smaller than centre of the distribution
 - Resolution better than the pixel size

6.1. INTRODUCTION

6.1.4. Detector requirements

6.1.4.3. Counting rate and dead time

- Achievable counting rate depends on
 - Detector response time
 - Time to transport charge carriers to form signal
 - Time to emit the scintillation light
 - Time needed to process the signals
 - Time needed to handle the data

6.1. INTRODUCTION

6.1.4. Detector requirements

6.1.4.3. Counting rate and dead time

Dead time (DT): Minimum time between true events at which these are counted separately

□ Non-paralysable detectors

- Second event $t < \tau \Rightarrow$ Not counted
- Second event $t > \tau \Rightarrow$ Counted
- DT fixed at τ

$$R = \frac{T}{1 + T\tau}$$

- T = true event rate
- R = counting rate
- $R\tau$ = Fraction of time system is dead
- $TR\tau$ = rate of loss of events = $T - R$

6.1. INTRODUCTION

6.1.4. Detector requirements

6.1.4.3. Counting rate and dead time

□ Paralyzable detectors

- Second event $t < \tau \Rightarrow$ not counted
 - DT extended τ from time of second event
- 3rd event at $t > \tau$ after 1st event & within τ after 2nd event \Rightarrow not counted
 - DT extended another τ
- DT is not fixed
 - Can become $\gg \tau$
 - i.e. 'extendable' dead time
- Counted: event which occurs at $t > \tau$
- Counting rate = rate of occurrences of time intervals $> \tau$ between events

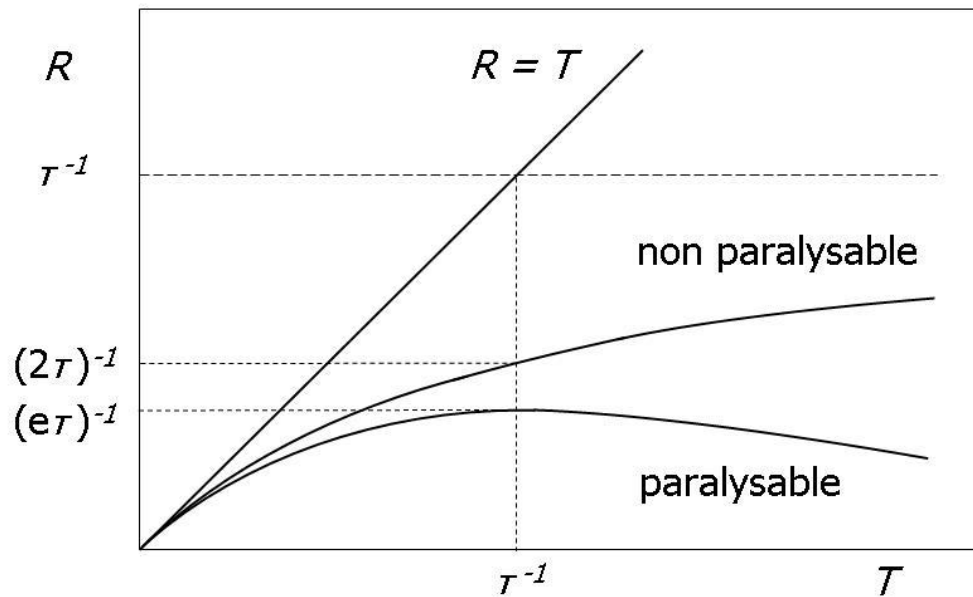
$$R = T e^{-T\tau}$$

6.1. INTRODUCTION

6.1.4. Detector requirements

6.1.4.3. Counting rate and dead time

- Relation between R and T for
 - non-paralysable and paralysable cases
 - if $\tau = 0$, then $R = T$

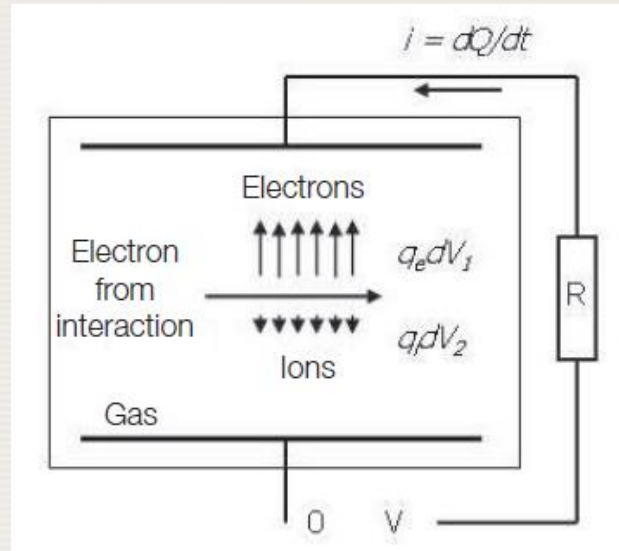


6.2. GAS FILLED DETECTORS

6.2.1. Basic principles

□ Energetic electrons

- Produce secondary electrons travelling through gas
- Secondary electrons drift to anode & ions to cathode



The mode of operation depends on applied voltage (V)

6.2. GAS FILLED DETECTORS

6.2.1. Basic principles

- Relatively low V
 - Recombination region
 - Produces weak electric field E
 - E too weak to efficiently separate the (-) and (+) charges
 - Some will recombine
 - Full signal not observed

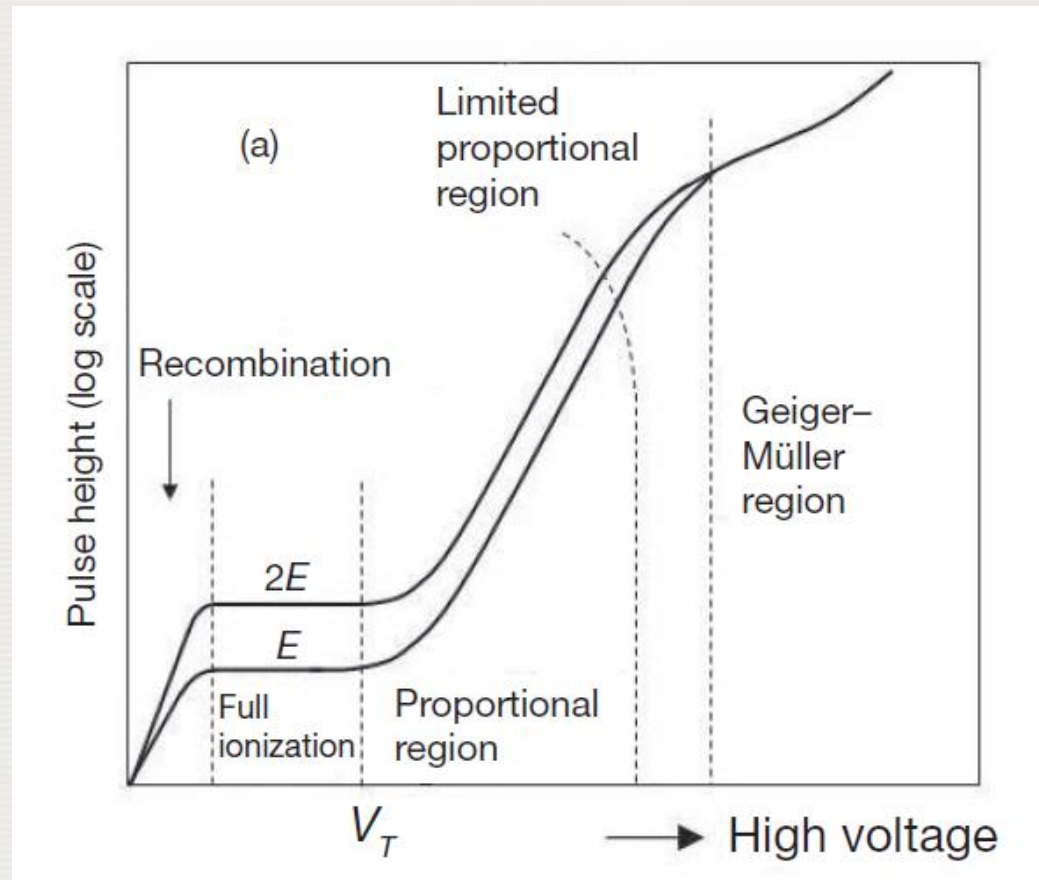
Increasing V decreases recombination

- Relatively high voltage V
 - Full ionization
 - Heavier charged particles & higher rates → higher V
 - Signal becomes constant over wide V range
 - Typical operating V of ionization chamber: 500 to 1000 V

6.2. GAS FILLED DETECTORS

6.2.1. Basic principles

- Pulse height as a function of applied high V for gas filled detectors

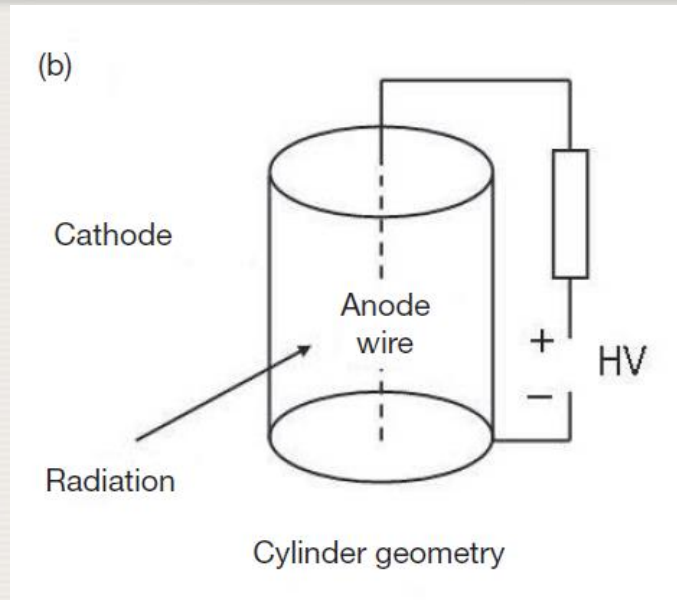


6.2. GAS FILLED DETECTORS

6.2.1. Basic principles

□ Operation at stronger electric field E

- Examples:
 - cylindrical detector geometry
 - thin anode wire in centre
 - metal cylinder as cathode
- $E(r) \propto V/r$
- At $V_T =$ threshold voltage
 - E near anode
 - Very strong
 - Drifting electron gains enough energy to ionize gas atom
 - Proportional region
 - For gain $M \approx 10^4$, M is independent of deposited energy
 - proportional counter
 - At normal temperature and pressure $E_T \approx 10^6$ V/m.
 - For parallel plate geometry with depth ~ 1 cm, $V_T \approx 10$ kV \rightarrow not practicable
 - Due to the r^{-1} dependence manageable V can be applied for proportional operation (1–3 kV)



6.2. GAS FILLED DETECTORS

6.2.1. Basic principles

- Operation at stronger electric field E
 - At further increased V
 - Space charge effects start to reduce effective E
 - Affect the gain
 - Process will start at lower V for higher primary ionization density events
 - **Limited proportionality** region is entered
 - At further increased V
 - Pulse height will become independent of the deposited energy
 - **Geiger–Müller** region is entered
 - V further increased
 - Ionization zone expands
 - Avalanche & significant amplification obtained

6.2. GAS FILLED DETECTORS

6.2.1. Basic principles

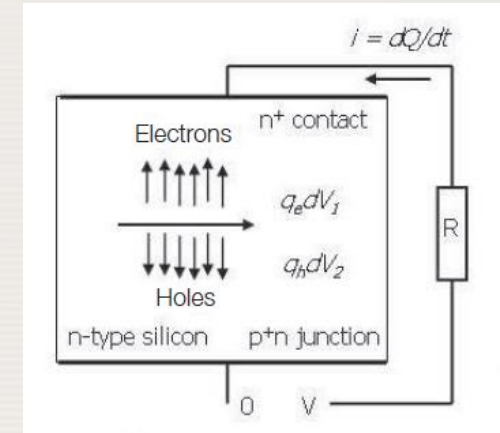
- Multi-wire proportional chamber (MWPC)
 - Alternate geometry
 - Many equidistant parallel anode wires
 - Pitch of 1–2 mm
 - Positioned in a plane inside a box
 - Walls are cathode planes
 - Employed in autoradiography
 - Micro-patterned detectors made with photo-lithography
 - Operate analogously to the MWPC
 - *Examples:*
 - Micro-strip gas chamber
 - Gas electron multiplier
 - Spatial resolutions are of the order of 0.1 mm

6.3. SEMICONDUCTOR DETECTORS

6.3.1. Basic principles

□ Semiconductor detector is a capacitor

- After interaction
 - Electrons lifted from valence into conduction band
 - Charge carriers transported in applied electric field
- Applying voltage difference to electrodes on opposite sides of a slab of semiconductor leads to a current that's too high for practical use as detector
- At room temperature,
 - Electrons are lifted from valence to conduction band by thermal excitation due to small gap ($E_{\text{gap}} \approx 1 \text{ eV}$)
 - Free electrons and holes cause a current
 - ⇒ Make into a diode and operate in reverse bias



6.3. SEMICONDUCTOR DETECTORS

6.3.1. Basic principles

□ *Example:* Silicon

- Semiconductor-electronics used to make diode structure
- N-type silicon
 - Doped with electron-donor impurities
 - Reduces number of holes
 - Electrons are the majority charge carriers
- P-type silicon
 - Doped with electron-acceptor impurities
 - Strongly reduces number of free electrons
 - Holes are the majority charge carriers

6.3. SEMICONDUCTOR DETECTORS

6.3.1. Basic principles

□ *Example:* Silicon

- Junction diode
 - Formed when n-type brought into contact with p-type material
 - Depletion region
 - Space charge zone results at junction
 - Due to diffusion of majority charge carriers
 - Reverse-biased
 - Positive voltage applied on n-type side with respect to p-type side
 - Depletion layer thickness increased
 - High enough voltage fully depletes layer
 - No free charge carriers left
 - Virtually no current flows
 - Only small current remains (**leakage or dark current**)

6.3. SEMICONDUCTOR DETECTORS

6.3.1. Basic principles

□ *Example:* Silicon

- Diode
 - n-type doped with impurities in narrow zone
 - makes p^+n junction
 - p^+ : high doping concentration
 - Use high-purity Si & blocking contact for further leakage current reduction
 - n^+ doping at n-type side
 - If the leakage current is still problematic, the temperature can be decreased
 - Use of high purity semiconductor material is important for reducing leakage current
 - Energy levels in the gap may trap charge carriers resulting from the interaction with radiation and the energy resolution of a detector would be reduced

6.3. SEMICONDUCTOR DETECTORS

6.3.1. Basic principles

- *Example:* Silicon → Other approaches to make a detector
 - Start with p-type material and make n⁺p junction diode
 - Apply a combination of surface oxidation and deposition of thin metal layer
 - Called surface barrier contacts
 - For thicknesses <1 mm it's possible to use intrinsic Si with p⁺ & n⁺ blocking contacts on opposite sides (p–i–n configuration)
 - For thicker detectors impurities are compensated for by introducing interstitial Li ions
 - Use slightly p-type intrinsic Si
 - Li ions act as electron donors
 - Li ions can be drifted ~10 mm
 - For large enough band gap metal contacts will suffice

6.3. SEMICONDUCTOR DETECTORS

6.3.1. Basic principles

□ Important parameters of electrons and holes

- Mobilities: μ_e and μ_h
- Lifetimes: τ_e and τ_h
- Drift velocity $v_{e,h}$ in electric field E
- The path length a charge carrier can travel in its lifetime is given by:

$$v_{e,h} \tau_{e,h} = \mu_{e,h} \tau_{e,h} E$$

- Mobilities for a given detector size and E
 - Provide drift times of charge carriers
 - Provide signal formation times
- Mobilities & lifetimes are related to the probability that charge carriers arrive at collecting electrodes

6.3. SEMICONDUCTOR DETECTORS

6.3.2. Semiconductor detectors

- Semiconductor properties relevant for nuclear medicine
 - Density ρ
 - Z_{eff} for photoelectric effect
 - E_{gap} and W value
 - $\mu_{e,h}$ and their products with lifetimes
 - Si primarily of interest for (position sensitive) detection of low energy X rays, beta particles and light quanta

| | ρ (g/cm ³) | Z_{eff} | E_{gap} (eV) | W^a (eV) | Mobility (cm ² /Vs) | | Mobility \times lifetime (cm ² /V) | |
|---|--------------------------------|------------------|--------------------------|---------------|-----------------------------------|---------|--|--------------------|
| | | | | | μ_e | μ_h | $\mu_e \tau_e$ | $\mu_h \tau_h$ |
| Si (300 K) | 2.3 | 14 | 1.12 | 3.6 | 1 350 | 480 | >1 | ~1 |
| Si (77 K) | | | 1.16 | 3.8 | 21 000 | 11 000 | >1 | >1 |
| Ge (77 K) | 5.3 | 32 | 0.72 | 3.0 | 36 000 | 42 000 | >1 | >1 |
| CdTe (300 K) | 6.2 | 50 | 1.44 | 4.7 | 1 100 | 80 | 3×10^{-3} | 2×10^{-4} |
| Cd _{0.8} Zn _{0.2} Te (CZT-300 K) | ~6 | 50 | 1.5–2.2 | ~5 | 1 350 | 120 | 4×10^{-3} | 1×10^{-4} |
| HgI ₂ (300 K) | 6.4 | 69 | 2.13 | 4.2 | 70 | 4 | 5×10^{-3} | 3×10^{-5} |

6.3. SEMICONDUCTOR DETECTORS

6.3.2. Semiconductor detectors

- Detection of X-rays of 300 eV - 60 keV
 - Si(Li)
 - Commercially available planar circular Li drifted p–i–n
 - Thickness up to 5mm
 - Diameters 4–20 mm
 - For typical $E=1000$ V/cm drift times to electrodes are on the order of tens of ns
 - Energy resolutions (FWHM) at 5.9 keV are 130–220 eV at 77 K
 - Position sensitive Si detectors commercially available with a large variety of pixel structures
 - Si detectors also used in personal dosimeters

6.3. SEMICONDUCTOR DETECTORS

6.3.2. Semiconductor detectors

- High resolution gamma-ray spectroscopy uses Ge detectors
 - Higher density & Z
 - Made of high purity material
 - Large volume detectors in coaxial geometry
 - Made of cylindrical crystals with core removed
 - High purity n-type or p-type used with corresponding junction
 - Contacts on outside and blocking contacts on inside
 - Operated at 77 K
 - Commercially available cylindrical detectors
 - Diameter ≤ 10 cm, height ≤ 10 cm
 - Drift times to electrodes ≤ 100 ns
 - Typical energy resolutions
 - 1 keV at 122 keV γ -ray energy
 - 2 keV at 1332 keV γ -ray energy

6.3. SEMICONDUCTOR DETECTORS

6.3.2. Semiconductor detectors

- CdTe (cadmium telluride) and CZT (cadmium zinc telluride)
 - Z is significantly higher than for Ge
 - Possible to operate at room temperature due to larger band gap
 - High purity n-type or p-type material is used
 - Worse energy resolution than Ge
 - e.g. 2.5% FWHM at 662 keV (primarily due to relatively short lifetime of holes, resulting in incomplete charge collection)
 - To observe the electron signal only use either or both:
 - Electronic correction techniques
 - Detectors with special electrode configurations (small pixels or grids)
 - Dimensions: $\sim 25 \times 25 \times 10 \text{ mm}^3$
 - 16×16 pixels detectors are available
 - e.g. used for SPECT innovation

6.3. SEMICONDUCTOR DETECTORS

6.3.2. Semiconductor detectors

- HgI_2 (mercury iodide) is attractive for efficient γ -ray detection
 - Large density and high Z
 - Room temperature operation possible due large band gap
 - Cons
 - Mobilities are low
 - Charge collection, in particular of holes, is poor
 - Application is limited to thicknesses ≤ 10 mm
 - $E = 2500$ V/cm
 - Areas $\approx 30 \times 30$ mm²

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.1. Basic principles

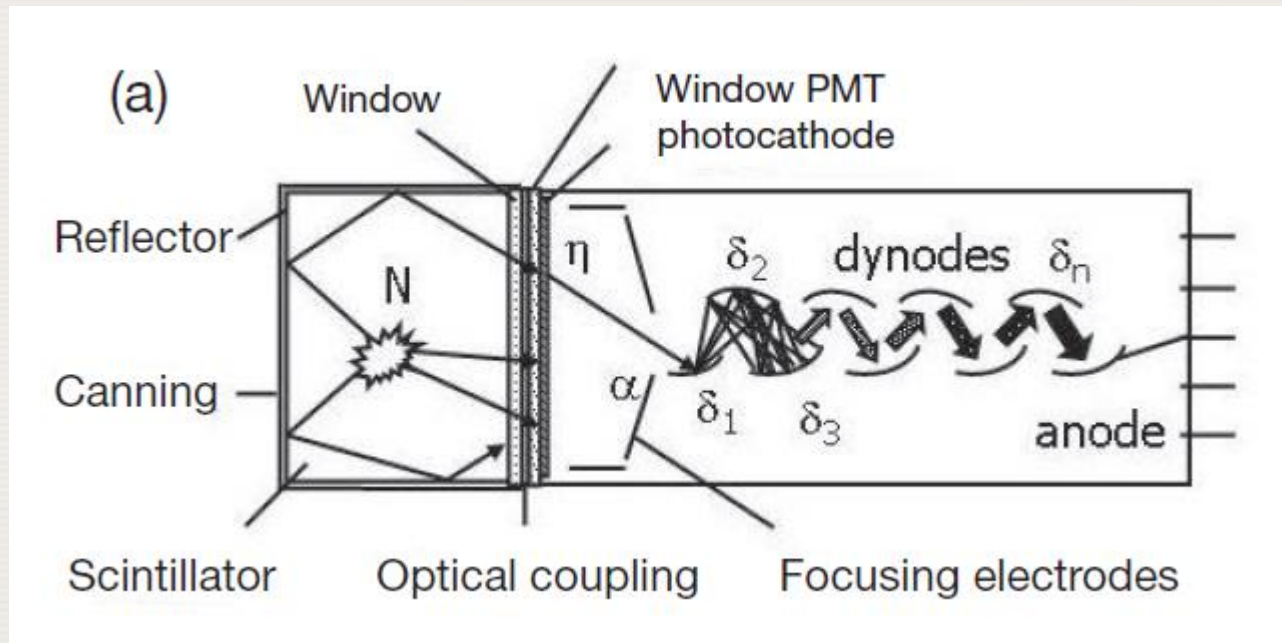
- ❑ **Scintillation** is prompt emission of light after radiation interaction
- ❑ In nuclear medicine, inorganic ionic crystals are most important
 - High density & Z
 - Fast response
 - High light yield
 - Large crystals can be grown
 - Primarily for X-ray and γ -ray detection
 - Metastable states (traps) are created in some materials
 - may live ms to months (storage phosphors)
- ❑ Organic scintillators are another group
 - Crystals, plastics and liquids
 - Low density & Z
 - Primarily for counting β particles

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.2. Light sensors

6.4.2.1. Photomultiplier tubes

- ❑ A scintillation crystal is coupled to a PMT to make a detector
- ❑ Inside of entrance window to the evacuated glass envelope is covered with a photocathode which converts photons into electrons



6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

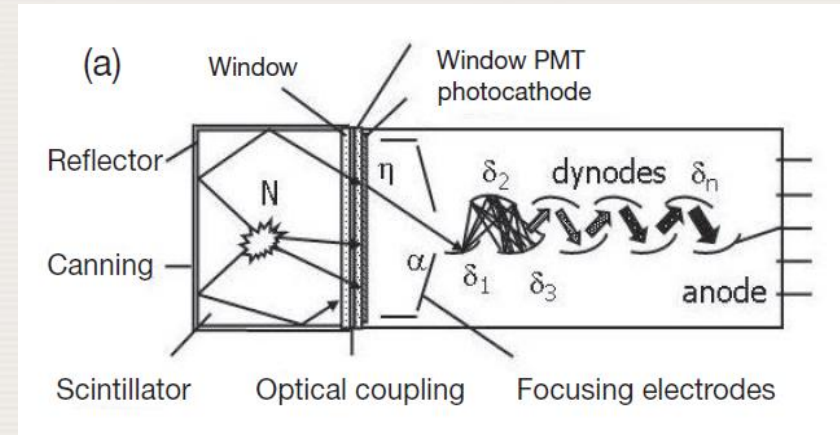
6.4.2. Light sensors

6.4.2.1. Photomultiplier tubes

□ Photocathode consists of thin layer of alkali materials with very low work functions

- Examples

- Bialkali K_2CsSb
- Multialkali $Na_2KSb:Cs$
- Negative electron affinity (NEA) material such as $GaAs:Cs,O$



- Conversion efficiency of PMT is called Quantum Efficiency η
 - Strongly wavelength dependent
 - At 400 nm, $\eta = 25\text{--}40\%$

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.2. Light sensors

6.4.2.1. Photomultiplier tubes

- Emitted electrons focused onto first **dynode** via electrode structure
 - Applied voltage = 200–500 V
 - Collection efficiency $\alpha \approx 95\%$
 - Typical materials are BeO–Cu, Cs₃Sb and GaP:Cs
 - The latter is an NEA material
 - Electrons released by secondary emission if electron hits dynode
 - Focused onto next dynode
 - Secondary electrons emitted again
 - N = Number of dynodes = 8–12
 - Last dynode (**anode**) provides signal
 - Multiplication factor
 - $\delta \approx 5$ per dynode at inter-dynode voltage = 100 V
 - First dynode has higher multiplication factor $\delta_1 \geq 10$
 - Improves single-electron pulse resolution & signal to noise ratio

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.2. Light sensors

6.4.2.1. Photomultiplier tubes

□ Signal properties

- Starting with N photons in the scintillator
- Assuming full light collection on the photocathode
- N_{el} = Number of electrons at anode is given by:

$$N_{\text{el}} = \delta_1 \delta^{n-1} \alpha \eta N$$

□ Gains of 10^6 – 10^7 are obtained

□ Negative high voltage (1000–2000 V) often used with anode at ground potential

□ Operational care

- Care must be taken of metal parts near the cathode
- Detector housing should never be opened with voltage on
- Exposure to daylight would damage the photocathode permanently

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.2. Light sensors

6.4.2.1. Photomultiplier tubes

PMTs

- Available with circular, square or hexagonal photocathodes
- Cathode diameters = 10 - 150 mm
- If diameter ~ 50 mm \Rightarrow length ~ 150 mm (including contact pins)
- Also available pixelated with multi-anode

Time resolution optimized by making special tubes with electron transit times as the anode, independent of cathode position where electron emitted

Electron transit time ~ 30 ns

Spread standard deviation ~ 250 ps

Signal rise time ~ 1.5 ns



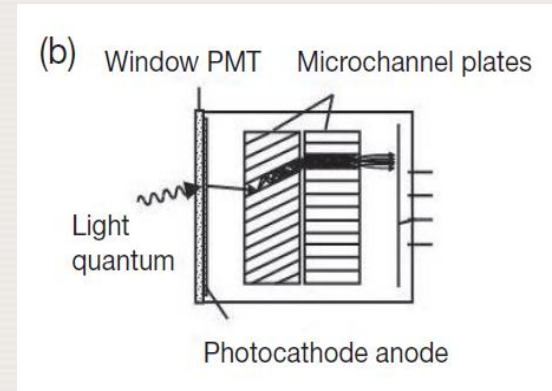
6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.2. Light sensors

6.4.2.1. Photomultiplier tubes

□ Microchannel plate (MCP) PMT

- Aimed at ultra-fast timing
- Replaces dynodes for electron multiplication
- Thickness ~ 1 mm
- Has large number of closely packed hollow glass tubes
- Channel diameter = 5–50 μm
- Inner tube surface is covered with a secondary emission material (e.g. PbO)
- The glass surfaces on the front and back side are covered with metal contacts
- Placed in vacuum
- 1000 V applied between contacts, positive on the back side



6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.2. Light sensors

6.4.2.1. Photomultiplier tubes

□ Microchannel plate (MCP)

- An electron enters glass tube on front side & hits wall
- Secondary electron emission occurs
 - Electrons pulled to back side by E
 - Hit channel wall & produce secondaries, etc.
 - Eventually leave tube at back
- Electron multiplication $\leq 10^4$

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.2. Light sensors

6.4.2.1. Photomultiplier tubes

- MCP-PMT uses 2 MCPs at close distance
 - Structure called **chevron**
 - Glass tubes at an angle
 - Prevent ions from gaining too much energy
 - At 3000 V, stable gains $\sim 10^6$
 - Advantage: short path length of electrons
 - Transit times \sim few ns
 - Transit time spreads \sim 100 ps
 - Commercially available as:
 - Circular with diameter = 10 mm
 - Square with multi-anode structures
 - Sensitive between 115 nm (MgF_2 window) - infrared

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.2. Light sensors

6.4.2.2. Silicon based photon sensors

☐ Si photodiodes preferred in some applications

- PMTs have large size, high voltages, small quantum efficiency and sensitivity to magnetic fields
- Si diodes are usually p–i–n structure (**PIN diodes**)
- Thickness = 2 mm including packaging
- Shapes: circular, rectangular or square, up to 30 mm × 30 mm
- Bias voltages < 150 V

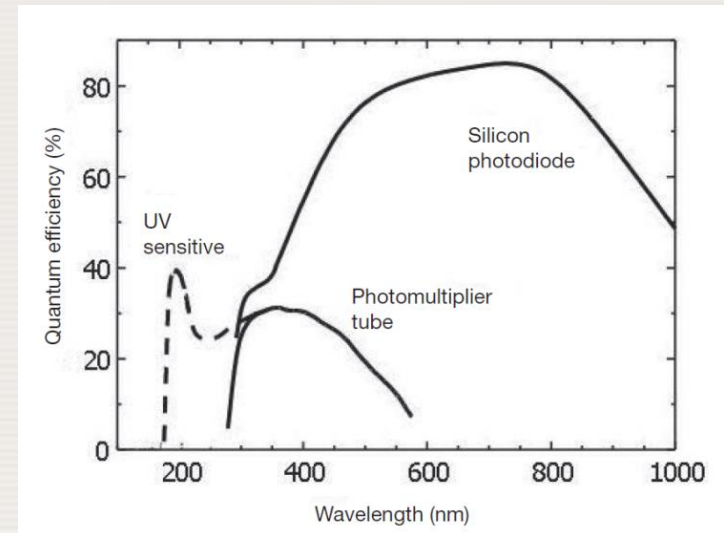
6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.2. Light sensors

6.4.2.2. Silicon based photon sensors

☐ Si photodiodes preferred in some applications

- Quantum efficiency can be > 80% at longer wavelengths
- Disadvantages
 - Large capacitance = 20–300 pF
 - Large leakage current ~ 1–10 nA
 - Significant noise level
 - Affects energy resolution negatively



6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.2. Light sensors

6.4.2.2. Silicon based photon sensors

□ Avalanche photodiode (APD)

- Semiconductor analogue to proportional counter
- A high E -field is created in small zone
 - Drifting electron can gain enough energy to produce (e-h) pair
 - An avalanche results
 - Critical field for multiplication = 10^7 V/m
- Higher $V \rightarrow$ higher gain
- Voltages applied = 50–1500 V depending on type
 - Gains are $M \lesssim 1000$
 - Lifts signal well above noise as compared to Si diode
 - At a certain gain, the advantage is optimal

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.2. Light sensors

6.4.2.2. Silicon based photon sensors

□ Avalanche photodiode (APD)

- Break-down voltage V_{br}
 - Spontaneous charge multiplication occurs
- At voltages $> V_{br}$
 - For gains of $M 10^5 - 10^6$
 - **Geiger** mode
 - Pulses are equal in magnitude
 - Signal quenching techniques have to be used
- Available as circular & square with areas = sub-mm² - 1 cm²
- Available with various pixelations
 - e.g. of 4×8 at 2.5 mm pitch & fill factor $\leq 40\%$

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.2. Light sensors

6.4.2.2. Silicon based photon sensors

□ Hybrid photomultiplier tube (HPMT)

- Voltage between photocathode & Si diode ~ 10 kV
- Si diode placed inside vacuum enclosure
- Photoelectrons accelerated in resulting E field
- Diode is relatively small
 - Reduces capacitance which reduces noise level
 - Need 3.6 eV to produce 1 e-h pair
 - 3000 e-h pairs produced per impinging electron
- Signals from one or more photons are well separated
- Possible overall gain with APD = 10^5
- Window diameters are as large as 70 mm

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.2. Light sensors

6.4.2.2. Silicon based photon sensors

□ Silicon photomultiplier (SiPM)

- Array of tiny APDs operating in Geiger mode
- Dimensions: $20 \times 20 \mu\text{m}^2$ to $100 \times 100 \mu\text{m}^2$
- Number of APDs per $\text{mm}^2 = 2500 - 100$
- Fill factor from $< 30\%$ to 80% for smallest to largest dimensions
- All APDs signals are summed
- Time spread $< 100 \text{ ps}$
- Excellent time resolutions

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.2. Light sensors

6.4.2.2. Silicon based photon sensors

□ Silicon photomultiplier (SiPM)

- Gains $M = 10^5 - 10^6$
 - Can easily obtain a signal from a single photon
 - Spontaneous Geiger pulses can be eliminated by setting a threshold above the one electron response
- Available arrays
 - 2×2 pixels and 4×4 pixels
 - $3 \times 3 \text{ mm}^2$ each
 - Pitch of 4 mm
 - A 16×16 pixel array of $50 \times 50 \text{ mm}^2$ (recently introduced)
 - Blue sensitive SiPMs have detection efficiency of 25% at 400 nm, including a 60% fill factor

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.3. Scintillator materials

6.4.3.1. Inorganic scintillators

- Inorganic scintillator bandgap has to be relatively large so as to:
 - $E_{\text{gap}} \geq 4 \text{ eV}$
 - Avoid thermal excitation
 - Allow scintillation photons to travel in material without absorption

- Thus: inorganic scintillators are based on ionic-crystal materials

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.3. Scintillator materials

6.4.3.1. Inorganic scintillators

- Three steps scintillation photons production
 1. Interaction with bulk material & thermalization of electrons and holes
 - Electrons go to bottom of conduction band
 - Holes go to top of the valence band
 2. Transport of charge carriers to intrinsic or dopant luminescence centres
 3. Interaction with these centres
 - Excitation
 - Relaxation
 - Scintillation

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

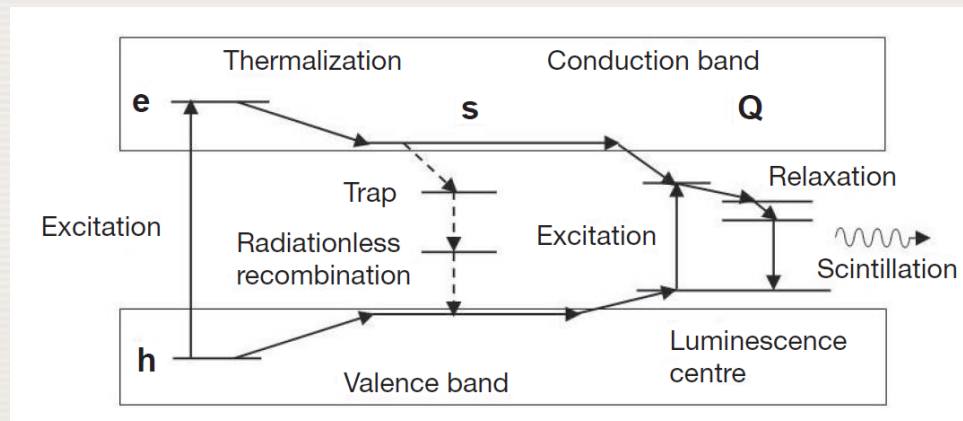
6.4.3. Scintillator materials

6.4.3.1. Inorganic scintillators

- Using this model, the number of photons N_{ph} produced under absorption of a gamma ray with energy E is:

$$N_{\text{ph}} = \frac{E}{\beta E_{\text{gap}}} SQ$$

- $E/\beta E_{\text{gap}}$ = number of e–h pairs at bandgap edge
- $\beta \approx 2.5$
- S & Q are the efficiencies of steps 2. and 3. in previous slide



6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.3. Scintillator materials

6.4.3.1. Inorganic scintillators

□ Specifications of some inorganic scintillators

| Scintillator | ρ (g/cm ³) | Z_{eff} | $1/\mu_{511}$ (mm) | Photoelectric effect (%) | λ_{max} (nm) | N_{ph} (photons/MeV) | R_{662} (%) | τ (ns) |
|--|--------------------------------|------------------|-----------------------|-----------------------------|--------------------------------|----------------------------------|------------------|----------------------|
| NaI:TI ^a | 3.67 | 51 | 29 | 17 | 410 | 41 000 | 6.5 | 230 |
| CsI:TI | 4.51 | 54 | 23 | 21 | 540 | 64 000 | 4.3 | 800, 10 ⁴ |
| BaF ₂ | 4.88 | | 23 | | 220 | 1500 | | 0.8 |
| | | | | | 310 | 10 000 | | 600 |
| Bi ₃ Ge ₄ O ₁₂ (BGO) | 7.1 | 75 | 10.4 | 40 | 480 | 8520 | | 300 |
| LaCl ₃ :Ce ^a | 3.86 | 49.5 | 28 | 15 | 350 | 49 000 | 3.3 | 25 |
| LaBr ₃ :Ce ^a | 5.07 | 46.9 | 22 | 13 | 380 | 67 000 | 2.8 | 16 |
| YAlO ₃ :Ce (YAP) | 5.5 | 33.6 | 21 | 4.2 | 350 | 21 000 | 4.4 | 25 |
| Lu _{0.8} Y _{0.2} Al:Ce (LuYAP) | 8.3 | 65 | 11 | 30 | 365 | 11 000 | | 18 |
| Gd ₂ SiO ₅ :Ce (GSO) | 6.7 | 59 | 14.1 | 25 | 440 | 12 500 | 9 | 60 |
| Lu ₂ SiO ₅ :Ce,Ca (LSO) | 7.4 | 66 | 11.4 | 32 | 420 | ~36 000 | 7 | 36–43 |
| Lu _{1.8} Y _{0.2} SiO ₅ : Ce (LYSO) | 7.1 | | 12 | | 420 | 30 000 | 7 | 40 |

^a Hygroscopic



6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.3. Scintillator materials

6.4.3.1. Inorganic scintillators

- ❑ The scintillators in the table are commercially available
- ❑ If hygroscopic, they are canned with reflective material
- ❑ Only BaF_2 and BGO have intrinsic luminescence centre
- ❑ Others have Tl^+ or Ce^{3+} ions as dopant luminescence centre
 - Ce doped scintillators show a relatively fast response
 - Of the order of tens of ns
 - Due to allowed $5d \rightarrow 4f$ dipole transition of the Ce ion
 - Tl doped scintillators much slower because these transitions are forbidden

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.3. Scintillator materials

6.4.3.1. Inorganic scintillators

- In general, mixed or co-doped crystals have advantages in:
 - Crystal growing
 - Response time
 - Light yield
 - Large variation due to $S < 1$
 - Afterglow effects

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.3. Scintillator materials

6.4.3.2. Organic scintillators — crystals, plastics and liquids

- ❑ Organic scintillators scintillation mechanism based on molecular transitions
 - Hardly affected by physical state of the material

- ❑ There are pure organic scintillator crystals such as
 - Anthracene
 - Plastics
 - Polystyrene
 - Liquids (Xylene)

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.3. Scintillator materials

6.4.3.2. Organic scintillators — crystals, plastics and liquids

- There are also solutions of organic scintillators in organic solid (plastic) and liquid solvents
 - Typical combinations: p-terphenyl in polystyrene (plastic) and p-terphenyl in toluene

- There are also systems with POPOP added for wavelength shifting. In general:
 - Organic scintillators luminesce at ~420 nm, have a light yield of ~10 000 photons/MeV of absorbed γ -ray energy
 - Decay times are about 2 ns

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.3. Scintillator materials

6.4.3.3. Storage phosphors — thermoluminescence /optically stimulated luminescence

□ Storage phosphor

- Analogous to inorganic scintillator
- Difference: a significant part of interaction energy is stored in long-living traps
 - These are the memory bits of a storage phosphor
- The lifetime must be long enough for the application considered

□ Readout is done by thermal (heating) or optical stimulation

- Electron lifted from the trap into the conduction band and transported to a luminescence centre
- The intensity of the luminescence is recorded
- Processes called thermoluminescence & optically/photon stimulated luminescence

6.4. SCINTILLATION DETECTORS AND STORAGE PHOSPHORS

6.4.3. Scintillator materials

6.4.3.3. Storage phosphors — thermoluminescence /optically stimulated luminescence

- ❑ LiF:Mg,Ti is widely used
 - Commercial name TLD-100
 - Sensitivity = 50 μGy to 1 Gy
- ❑ LiF:Mg,Cu,P (GR-200)
 - Newer & more sensitive
 - Sensitivity = 0.2 μGy to 1 Gy
- ❑ $\text{Al}_2\text{O}_3\text{:C}$
 - Optically stimulated luminescent material
 - Recently introduced
 - Sensitivity = 0.3 μGy to 30 Gy
- ❑ Also used in radiography
- ❑ Used for dosimetry for > 50 years
 - Thermoluminescence dosimeter